

CERTIFICATE OF ANALYSIS

ERM[®]-EB314a

AISi11Cu2Fe

	Certified value ¹⁾	Uncertainty ²⁾
Element	Mass fraction in %	
Si	11.51	± 0.15
Fe	0.992	± 0.017
Cu	2.08	± 0.07
Mn	0.404	± 0.008
Mg	0.196	± 0.004
Cr	0.0574	± 0.0012
Ni	0.242	± 0.006
Zn	1.100	± 0.015
Ti	0.188	± 0.004
Pb	0.189	± 0.010
Sn	0.201	± 0.004
Mass fraction in mg/kg		
As	28	± 7
Be	4.65	± 0.22
Bi	92	± 6
Cd	5.2	± 1.0
Co	74	± 4
Ga	164	± 4
Sb	102	± 19
V	277	± 7
Zr	103	± 3

¹⁾ Unweighted mean value of the means of accepted sets of data, each set being obtained by at least 6 laboratories and/or with different methods of measurement. The values are traceable to the SI (Système International d'Unités) by the use of pure substances of known stoichiometry for calibration.

²⁾ Estimated expanded uncertainty *U* with a coverage factor of *k* = 2, corresponding to a level of confidence of about 95 %, as defined in the ISO/IEC Guide 98-3:2008 [Uncertainty of measurement -- Part 3: Guide to the expression of uncertainty in measurement (GUM:1995)].

This certificate is valid until 02/2066.

DESCRIPTION OF THE SAMPLE

ERM-EB314a was prepared by atomisation of the melt in an inert gas stream with subsequent spray-compacting of the material. The Reference Material is available in the form of discs (50 mm diameter and 40 mm height).

Accepted as an ERM®, Berlin, 2016-02-08

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NOTE

European Reference Material ERM®-EB314a was produced and certified under the responsibility of BAM Federal Institute for Materials Research and Testing in cooperation with the Committee of Chemists of the GDMB, Society for Mining, Metallurgy, Resource and Environmental Technology according to the principles laid down in the technical guidelines of the European Reference Materials® co-operation agreement between BAM-LGC-IRMM. Information on these guidelines is available on the Internet (<http://www.erm-crm.org>).

INTENDED USE

The CRM is intended for establishing or checking the calibration of optical emission and X-ray spectrometers (excluding micro-analysis) for the analysis of samples of similar matrix composition. The minimum sample size for wet chemical analysis is 0.1 g.

INSTRUCTIONS FOR USE

Before use, the surface of the material must be prepared by milling or turning on a lathe. For wet chemical analysis chips have to be prepared by turning or milling of the sample surface.

MEANS OF ACCEPTED DATA SETS

Certified values
Mass fraction in %

Line no.	Si	Fe	Cu	Mn	Mg	Cr	Ni	Zn	Ti	Pb	Sn
1	11.21	0.971	2.008	0.394	0.190	0.0558	0.227	1.074	0.185	0.173	0.195
2	11.37	0.981	2.020	0.396	0.192	0.0560	0.231	1.074	0.185	0.176	0.198
3	11.42	0.982	2.037	0.401	0.192	0.0563	0.238	1.081	0.185	0.176	0.200
4	11.42	0.984	2.074	0.402	0.193	0.0564	0.239	1.095	0.186	0.178	0.200
5	11.43	0.987	2.076	0.403	0.194	0.0564	0.239	1.097	0.188	0.183	0.200
6	11.47	0.987	2.076	0.404	0.194	0.0570	0.240	1.107	0.189	0.194	0.201
7	11.49	0.988	2.094	0.405	0.197	0.0574	0.241	1.114	0.189	0.199	0.201
8	11.50	0.995	2.095	0.407	0.199	0.0574	0.241	1.115	0.191	0.201	0.201
9	11.58	0.996	2.103	0.407	0.199	0.0579	0.248	1.120	0.191	0.201	0.205
10	11.67	1.002	2.109	0.408	0.201	0.0581	0.248	1.122	0.194	0.211	0.205
11	11.76	1.004	2.114	0.410	0.206	0.0582	0.249	---			0.206
12	11.83	1.020	2.117	0.415		0.0597	0.252	---			
13		---				0.0601	0.252				
M	11.51	0.992	2.077	0.404	0.196	0.0574	0.242	1.100	0.188	0.189	0.201
s_M	0.18	0.013	0.037	0.006	0.005	0.0013	0.008	0.019	0.004	0.014	0.004
\bar{s}_i	0.08	0.008	0.014	0.004	0.003	0.0006	0.005	0.011	0.002	0.003	0.003

Certified values
Mass fraction in mg/kg

Line no.	As	Be	Bi	Cd	Co	Ga	Sb	V	Zr
1	21.4	---	86.7	3.83	69.2	---	90.2	271.0	97.0
2	26.0	4.18	88.4	3.94	70.8	159.1	94.9	274.4	99.8
3	26.2	4.46	88.7	4.43	72.3	160.2	96.8	274.8	99.9
4	28.1	4.55	91.7	5.00	72.6	161.6	101.7	275.7	102.1
5	29.8	4.74	91.9	5.13	73.1	162.7	102.4	276.7	103.8
6	34.8	4.80	93.7	5.44	73.8	163.0	106.6	278.1	103.8
7		4.89	95.5	5.59	74.1	165.3	107.0	279.2	104.2
8		4.90	101.8	5.67	74.6	166.3	110.5	280.4	105.9
9			---	5.98	75.3	169.7	110.7	280.6	107.0
10				6.10	77.1	171.8		281.9	
11				6.55	77.9				
M	27.7	4.65	92.3	5.24	73.7	164.4	102.3	277.3	102.6
s_M	4.5	0.27	4.9	0.88	2.6	4.3	7.2	3.4	3.2
\bar{s}_i	1.4	0.05	6.2	0.29	0.8	1.6	1.7	3.9	1.6

The laboratory mean values have been examined statistically to eliminate outlying values. Each laboratory mean consists of at least 3 but usually 6 single values.

Where " --- " appears in the table it indicates that an outlying value has been omitted (Grubbs 95 %, Cochran 99 %).

M : mean of laboratory means

s_M : standard deviation of laboratory means

\bar{s}_i : averaged repeatability standard deviation (square root of the mean of laboratory variances)

ANALYTICAL METHOD USED FOR CERTIFICATION

Element	Line no.	Method
Si	1, 2, 3, 6, 7, 9, 10, 12 4, 8 5 11	ICP-OES, dissolution with NaOH Spectrophotometry Gravimetry XRF
Fe	1, 3, 6, 7, 9, 10, 12 2 4, 11, 13 5 8	ICP-OES, dissolution with NaOH XRF ICP-OES, dissolution with acid ICP-OES INAA
Cu	1, 3, 5, 7, 8, 9, 11 2 4 6 10, 12	ICP-OES, dissolution with NaOH INAA ICP-OES XRF ICP-OES, dissolution with acid
Mn	1, 7 2 3, 4, 6, 8, 10, 11, 12 5 9	ICP-OES, dissolution with acid INAA ICP-OES, dissolution with NaOH ICP-OES XRF
Mg	1, 6, 7, 9 2, 3, 4, 10, 11 5 8	ICP-OES, dissolution with acid ICP-OES, dissolution with NaOH ICP-OES XRF
Cr	1, 10, 12 2 3, 4, 5, 8, 9, 11, 13 6 7	ICP-OES, dissolution with acid INAA ICP-OES, dissolution with NaOH ICP-OES XRF
Ni	1 2, 5, 6, 9, 10, 11, 12, 13 3 4, 7 8	INAA ICP-OES, dissolution with NaOH ICP-OES ICP-OES, dissolution with acid XRF
Zn	1 2, 12 3 4, 5, 6, 8, 9, 10, 11 7	XRF ICP-OES, dissolution with acid INAA ICP-OES, dissolution with NaOH ICP-OES
Ti	1 2, 3, 4, 6, 7, 8 5 9, 10	ICP-OES ICP-OES, dissolution with NaOH XRF ICP-OES, dissolution with acid
Pb	1, 5, 6, 9 2, 3, 4, 7 8 10	ICP-OES, dissolution with NaOH ICP-OES, dissolution with acid ICP-OES INAA

Element	Line no.	Method
Sn	1	XRF
	2, 4, 5, 7, 8, 9, 11	ICP-OES, dissolution with NaOH
	3, 10	ICP-OES, dissolution with acid
	6	ICP-OES
As	1, 2, 3	ICP-OES, dissolution with acid
	4	INAA
	5	ICP-MS
	6	ICP-OES
Be	2, 3, 4	ICP-OES, dissolution with acid
	5	ICP-OES
	6, 7, 8	ICP-OES, dissolution with NaOH
Bi	1, 5	ICP-OES, dissolution with acid
	2, 3, 6, 8	ICP-OES, dissolution with NaOH
	4	ICP-OES
	7	ICP-MS, dissolution with acid
Cd	1, 4, 7	ICP-OES, dissolution with acid
	2	INAA
	3, 5, 8, 11	ICP-OES, dissolution with NaOH
	6	ICP-OES
	9	GFAAS
	10	ICP-MS, dissolution with acid
Co	1, 2, 7, 8	ICP-OES, dissolution with acid
	3	INAA
	4	ICP-MS, dissolution with acid
	5	ICP-OES
	6, 9, 10, 11	ICP-OES, dissolution with NaOH
Ga	2	INAA
	3	ICP-OES
	4	ICP-MS, dissolution with acid
	5, 6, 8, 9	ICP-OES, dissolution with NaOH
	7, 10	ICP-OES, dissolution with acid
Sb	1, 5, 8	ICP-OES, dissolution with NaOH
	2, 3, 9	ICP-OES, dissolution with acid
	4	ICP-OES
	6	INAA
	7	ICP-MS
V	1, 2, 7	ICP-OES, dissolution with NaOH
	3	XRF
	4	ICP-OES
	5, 6, 8, 9, 10	ICP-OES, dissolution with acid
Zr	1	XRF
	2, 4, 5, 7	ICP-OES, dissolution with NaOH
	3, 8, 9	ICP-OES, dissolution with acid
	6	ICP-OES

Abbreviations:

- ICP-OES: Inductively coupled plasma optical emission spectrometry
 INAA: Instrumental neutron activation analysis
 GFAAS: Graphite furnace atomic absorption spectrometry
 ICP-MS: Inductively coupled plasma mass spectrometry
 XRF: X-ray fluorescence spectrometry

STORAGE

The material should be stored in a dry and clean environment at room temperature (approx. 20 °C).

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TECHNICAL REPORT

A detailed technical report describing the analysis procedures and the treatment of the analytical data used to certify ERM®-EB314a is available on request or can be downloaded from BAM website (www.bam.de/en/fachthemen/referenzmaterialien/index.htm).

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